

650V GaN HEMT

Description

The CC65H900DNZI Series 650V, 900mΩ gallium nitride (GaN) FETs are normally-off devices.

Classicchip GaN FETs offer better efficiency through lower gate charge, faster switching speeds, and lower dynamic onresistance, delivering significant advantages over traditional silicon (Si) devices.

Classicchip is a leading-edge wide band gap supplier with world-class innovation .

Automotive

- Adapter
- Renewable energy
- Telecom and data-com
- Servo motors
- Industrial
- Automotive

General Features

Easy to drive—compatible with standard gate drivers

Low conduction and switching losses

RoHS compliant and Halogen-free

Benefits

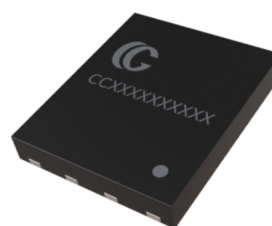
Increased efficiency through fast switching

Increased power density

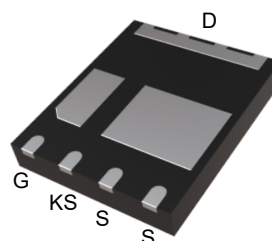
Reduced system size and weight

Ordering Information

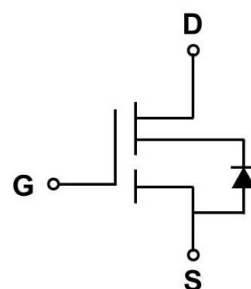
Part Number	Package	Package Configuration
CC65H900DNZI	DFN5*6	Source



top



bottom



Circuit Symbol

Features

BV_{DSS}	$R_{DS(on)}$	I_{DS}	Q_G
650V	900 mΩ	3.4A	6nC

Absolute Maximum Ratings

$T_C=25^{\circ}\text{C}$ unless otherwise stated

Symbol	Parameter		Limit value	Unit
V_{DSS}	Drain to source voltage ($T_J = -55^{\circ}\text{C}$ to 150°C)		650	V
$V_{(TR)DSS}$	Drain to source voltage-transient ^a		800	
V_{GSS}	Gate to source voltage		-20 ~ +20	
I_D	Continuous drain current @ $T_C=25^{\circ}\text{C}$ ^b		3.4	A
	Continuous drain current @ $T_C=125^{\circ}\text{C}$ ^b		1.6	
I_{DM}	Pulse drain current (pulse width: 100 μs)		5	A
P_D	Maximum power dissipation @ $T_C=25^{\circ}\text{C}$		21	W
T_C	Operating temperature	Case	-55 ~ 150	$^{\circ}\text{C}$
T_J		Junction	-55 ~ 150	$^{\circ}\text{C}$
T_S	Storage temperature		-55 ~ 150	$^{\circ}\text{C}$

a. In off-state, spike duty cycle $D < 0.01$, spike duration $< 1\mu\text{s}$

b. For increased stability at high current operation

Thermal Resistance

Symbol	Parameter	Limit value	Unit
$R_{\theta JC}$	Junction-to-case	6	°C /W

Electrical Parameters

$T_J=25^{\circ}\text{C}$ unless otherwise stated

Symbol	Parameter	Min	Typ	Max	Unit	Test Conditions
Forward Device Characteristics						
$V_{(BL)DSS}$	Drain-source voltage	650	-	-	V	$V_{GS}=0\text{V}$
$V_{GS(th)}$	Gate threshold voltage	1.2	1.7	2	V	$V_{DS}=1\text{V}, I_{DS}=1\text{mA}$
$\Delta V_{GS(th)}/T_J$	Gate threshold voltage temperature coefficient	-	-7	-	mV/ $^{\circ}\text{C}$	
$R_{DS(on)}$	Drain-source on-Resistance	-	900	1080	m Ω	$V_{GS}=10\text{V}, I_D=1\text{A}, T_J=25^{\circ}\text{C}$
		-	1900	-		$V_{GS}=10\text{V}, I_D=1\text{A}, T_J=150^{\circ}\text{C}$
I_{DSS}	Drain-to-source leakage current	-	-	10	μA	$V_{DS}=650\text{V}, V_{GS}=0\text{V}, T_J=25^{\circ}\text{C}$
		-	-	100		$V_{DS}=650\text{V}, V_{GS}=0\text{V}, T_J=150^{\circ}\text{C}$
I_{GSS}	Gate-to-source forward leakage current	-	-	± 100	nA	$V_{GS}=\pm 20\text{V}$
C_{ISS}	Input capacitance	-	400	-	pF	$V_{GS}=0\text{V}, V_{DS}=400\text{V}, f=1\text{MHz}$
C_{OSS}	Output capacitance	-	9.2	-		
C_{RSS}	Reverse capacitance	-	3.8	-		
Q_G	Total gate charge	-	6	-	nC	$V_{DS}=400\text{V}, V_{GS}=0\text{V to }10\text{V}, I_D=1\text{A}$
Q_{GS}	Gate-source charge	-	1.8	-		
Q_{GD}	Gate-drain charge	-	1.2	-		
Q_{OSS}	Output charge	-	12	-	nC	$V_{GS}=0\text{V}, V_{DS}=0\text{V to }400\text{V}, f=1\text{MHz}$
$t_{D(on)}$	Turn-on delay	-	3.4	-	ns	$V_{DS}=400\text{V}, V_{GS}=0\text{V to }10\text{V}, I_D=2.1\text{A},$ $R_{G-on(ext)}=6.8\Omega, R_{G-off(ext)}=2.2\Omega,$ $L=250\mu\text{H}$
t_R	Rise time	-	5.3	-		
$t_{D(off)}$	Turn-off delay	-	7.6	-		
t_F	Fall time	-	27	-		

Electrical Parameters

$T_J=25^{\circ}\text{C}$ unless otherwise stated

Symbol	Parameter	Min	Typ	Max	Unit	Test Conditions
Reverse Device Characteristics						
V_{SD}	Source-Drain reverse voltage	-	3.1	-	V	$V_{GS}=0\text{V}$, $I_{SD}=2.5\text{A}$
t_{RR}	Reverse recovery time	-	14	-	ns	$I_F=2.5\text{A}$, $V_{DD}=400\text{V}$, $dI_F/dt=165\text{A}/\mu\text{s}$
Q_{RR}	Reverse recovery charge	-	6.5	-	nC	

Typical Characteristics

$T_J = 25^\circ\text{C}$ unless otherwise stated

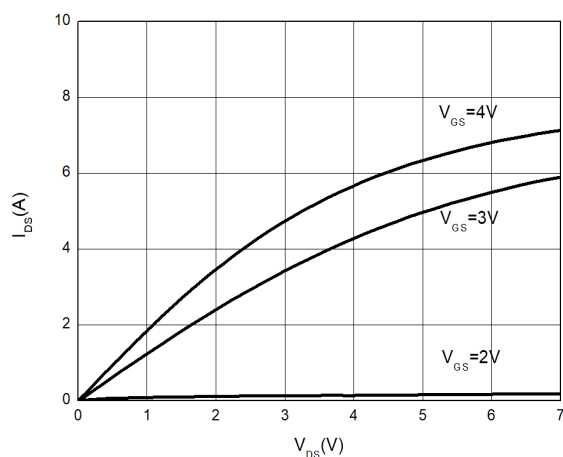


Figure 1. Typical Output Characteristics $T_J = 25^\circ\text{C}$

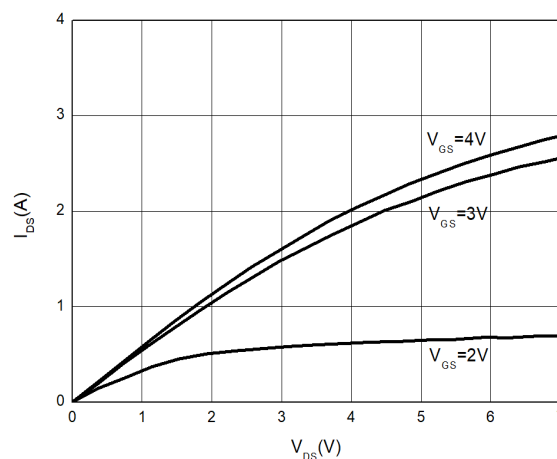


Figure 2. Typical Output Characteristics $T_J = 125^\circ\text{C}$

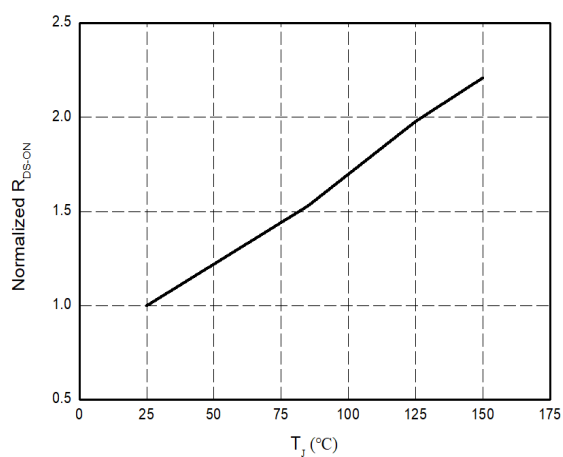


Figure 3. Normalized On-resistance

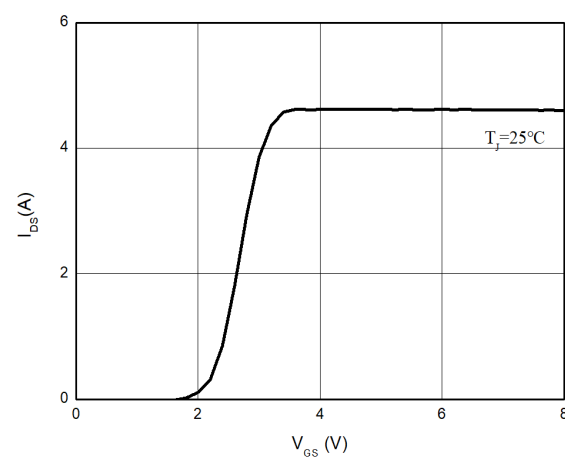


Figure 4. Typical Transfer Characteristics $T_J = 25^\circ\text{C}$

Typical Characteristics

$T_J=25^\circ\text{C}$ unless otherwise stated

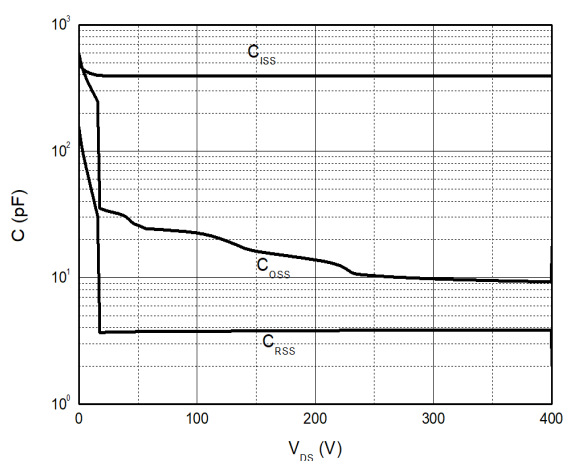


Figure 5. Typical Capacitance (f=1MHz)

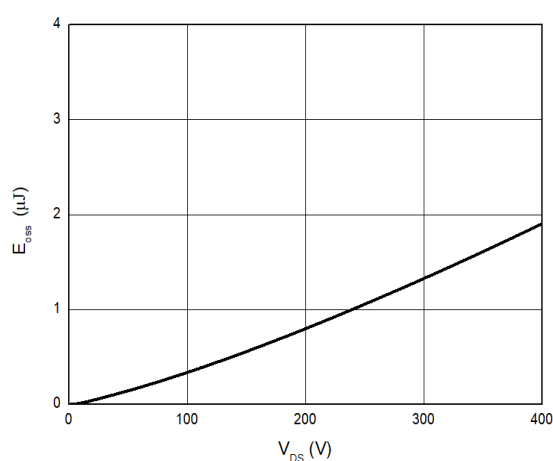


Figure 6. Typical C_{oss} Stored Energy

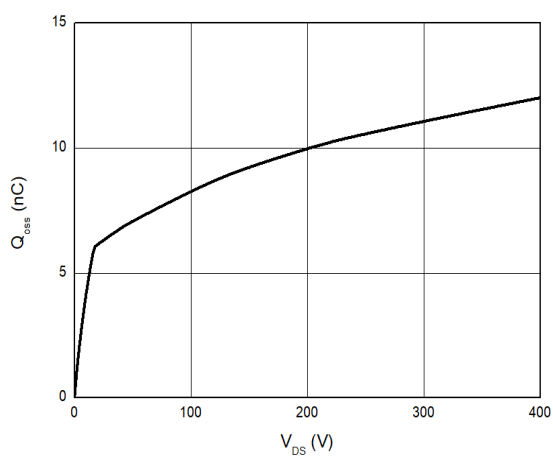


Figure 7. Typical Q_{oss}

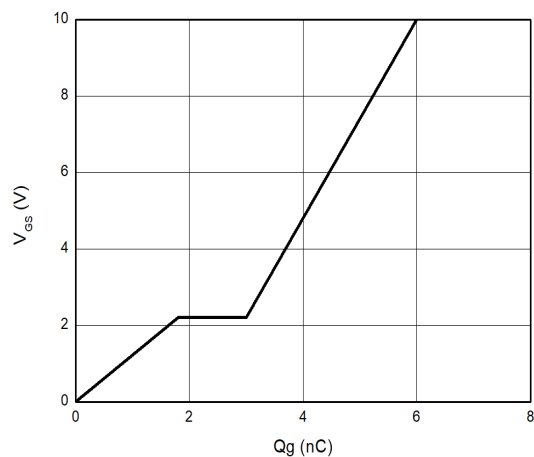


Figure 8. Typical Gate Charge ($V_{DS}=400\text{V}$, $I_D=1\text{A}$)

Typical Characteristics

$T_J=25^\circ\text{C}$ unless otherwise stated

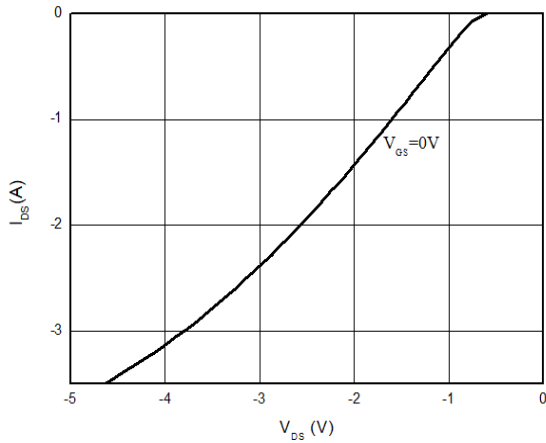


Figure 9. Channel Reverse Characteristics $T_J=25^\circ\text{C}$

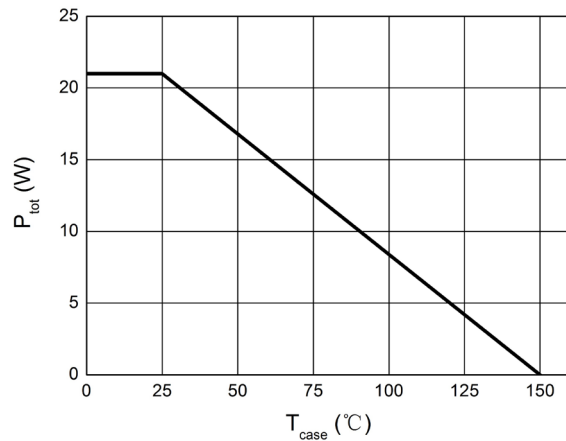


Figure 10. Power Dissipation

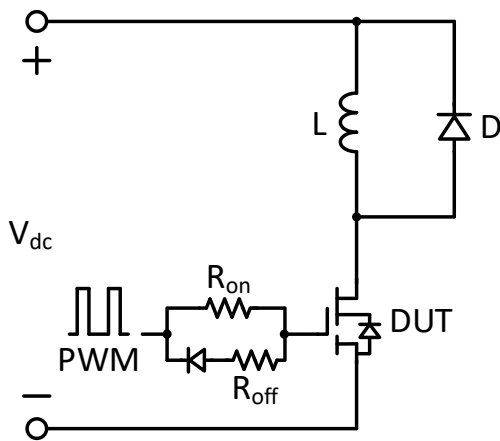


Figure 11 Switching times with inductive load

$V_{DS}=400\text{V}$, $V_{GS}=0\text{V}$ to 10V , $I_D=2.1\text{A}$,
 $R_{G-on(ext)}=6.8\Omega$, $R_{G-off(ext)}=2.2\Omega$, $L=250\mu\text{H}$

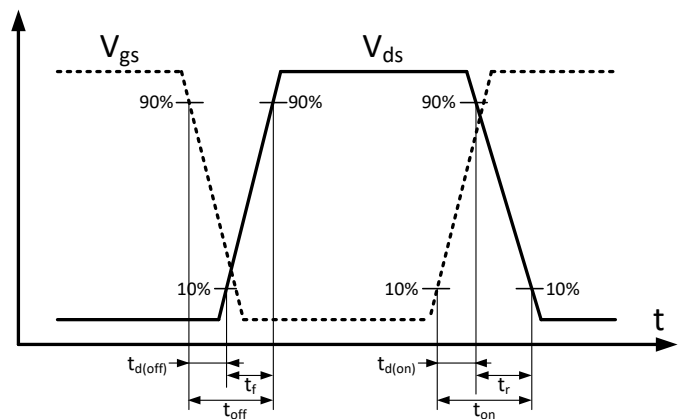
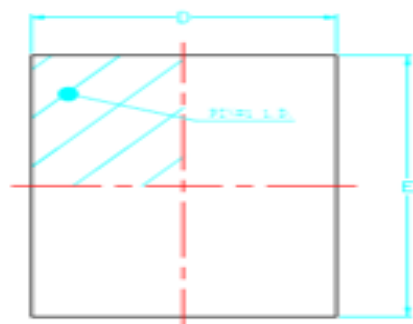
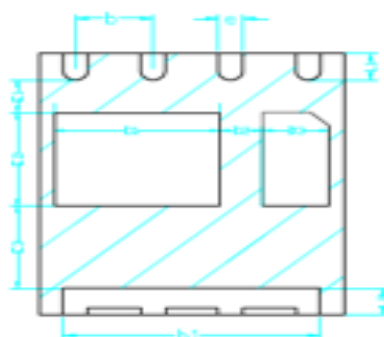


Figure 12. Switching times with waveform

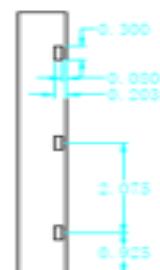
PACKAGE DIMENSIONS



TOP VIEW



BOTTOM VIEW



SIDE VIEW



SIDE VIEW

符号	尺寸 (单位: mm)		
	最小值	标准值	最大值
A	0.80	0.90	1.00
A1	0.203Ref		
A2	——	0.02	0.05
D	4.90	5.00	5.10
E	5.90	6.00	6.10
D1	2.61	2.71	2.81
D2	0.60	0.70	0.80
D3	0.99	1.09	1.19
E1	0.65	0.75	0.85
E2	2.05	2.15	2.25
E3	1.80	1.90	2.00
b	1.17	1.27	1.37
b1	4.11	4.21	4.31
e	0.30	0.40	0.50
L1	0.50	0.60	0.70
L2	0.50	0.60	0.70